

**Search Notes**

Application/Control No.

10/825,503

Examiner

David E. Bochna

Applicant(s)/Patent under  
Reexamination

KIM, JUNG-HOON

Art Unit

3679

**SEARCHED**

Class	Subclass	Date	Examiner
285	7	12/6/2006	DB
	184		
	273		
	282		
15	410		
	351		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR